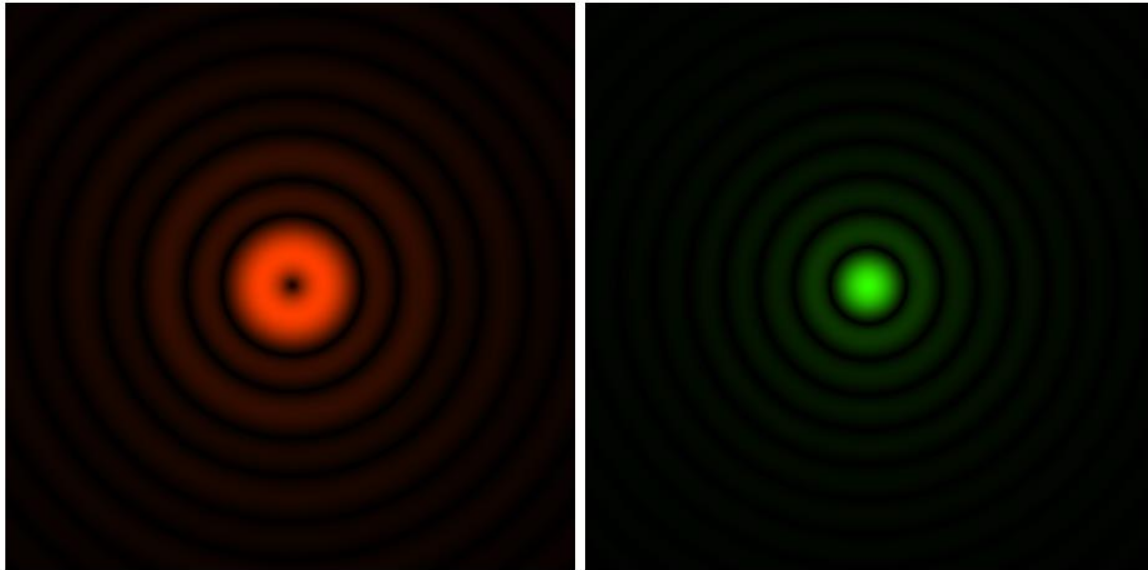


Principle of Stimulated Emission Depletion (STED) Microscopy

Abstract



Stimulated Emission Depletion (STED) Microscopy describes a commonly used technique to achieve super resolution in biological applications. In this method two laser beams – one normal, one transformed into a donut-mode – are superimposed onto a fluorescent specimen. By using excitation and depletion of the fluorescent processes and exploiting the resulting saturation effects, the back reflected light exhibits a much higher resolution compared to usual microscopy techniques (e.g., widefield microscopy). In this document the basic setup of such a device is presented. For modeling the saturation effect, an equivalent aperture is applied in the focal region.

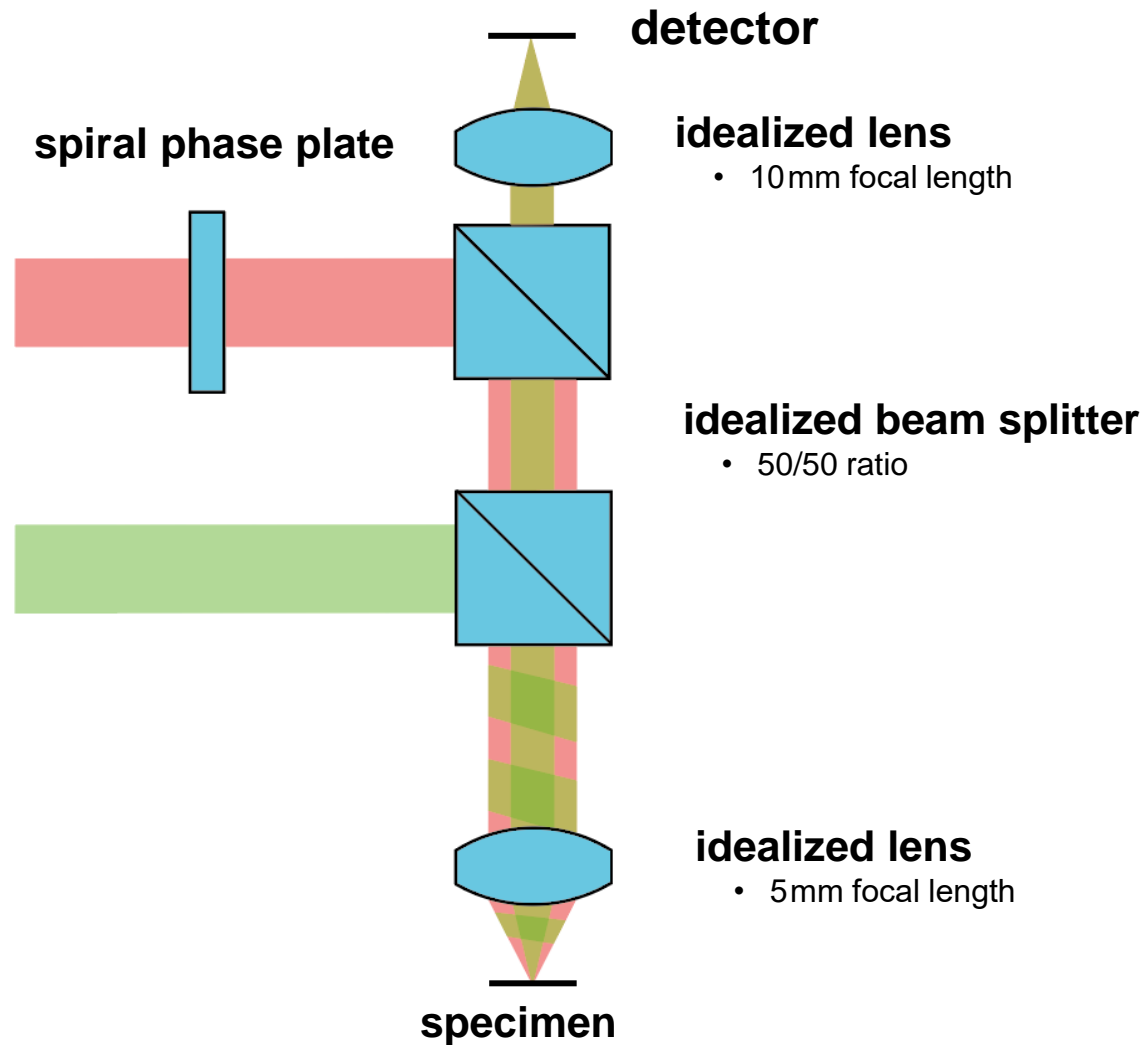
Task Description

depletion laser

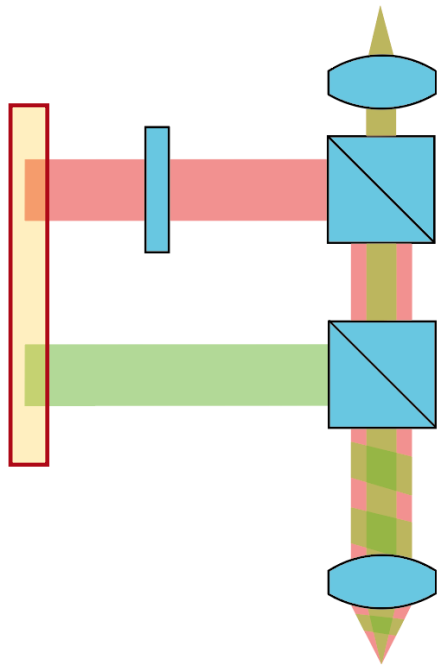
- plane wave
- wavelength 632.8nm
- diameter 10mm x 10mm

excitation laser

- plane wave
- wavelength 532nm
- diameter 10mm x 10mm



Multiple Light Source



The *Multiple Light Source* allows the user to include different sources in a single system. They can also be shifted with respect to each other.

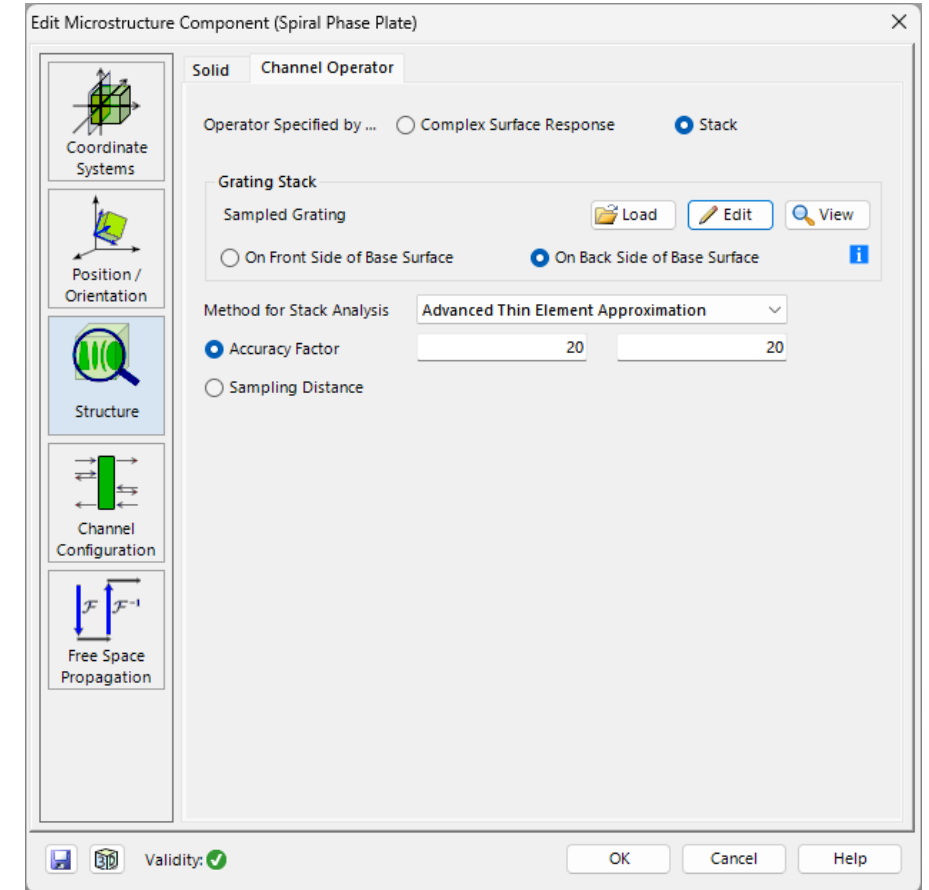
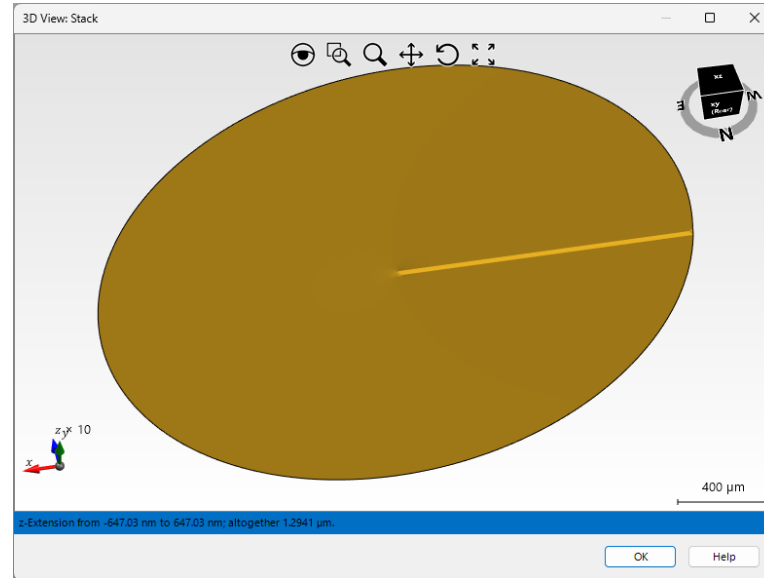
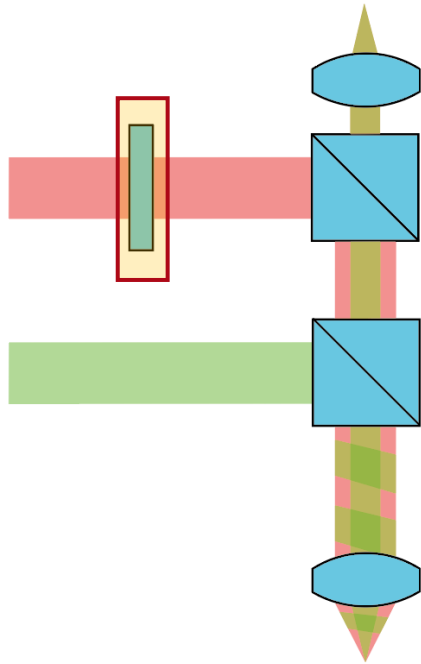
Multiple Light Source

Light Source Name	Light Source	Use
1 excitation laser	Plane Wave	<input checked="" type="checkbox"/>
2 depletion laser	Plane Wave	<input checked="" type="checkbox"/>

Wavelength: 532 nm
Weight: 1

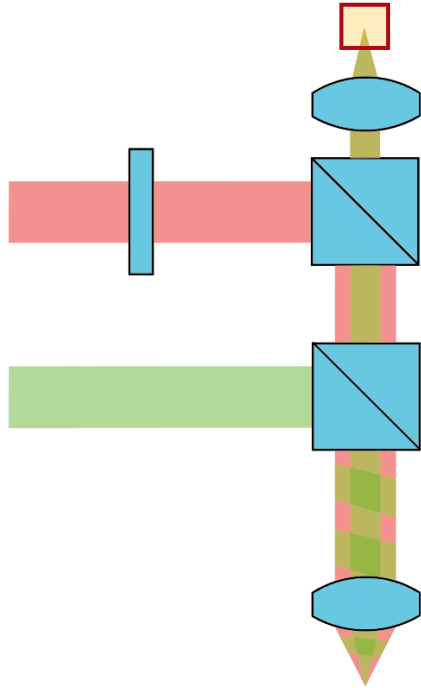
Wavelength: 632.8 nm
Weight: 1

Spiral Phase Plate



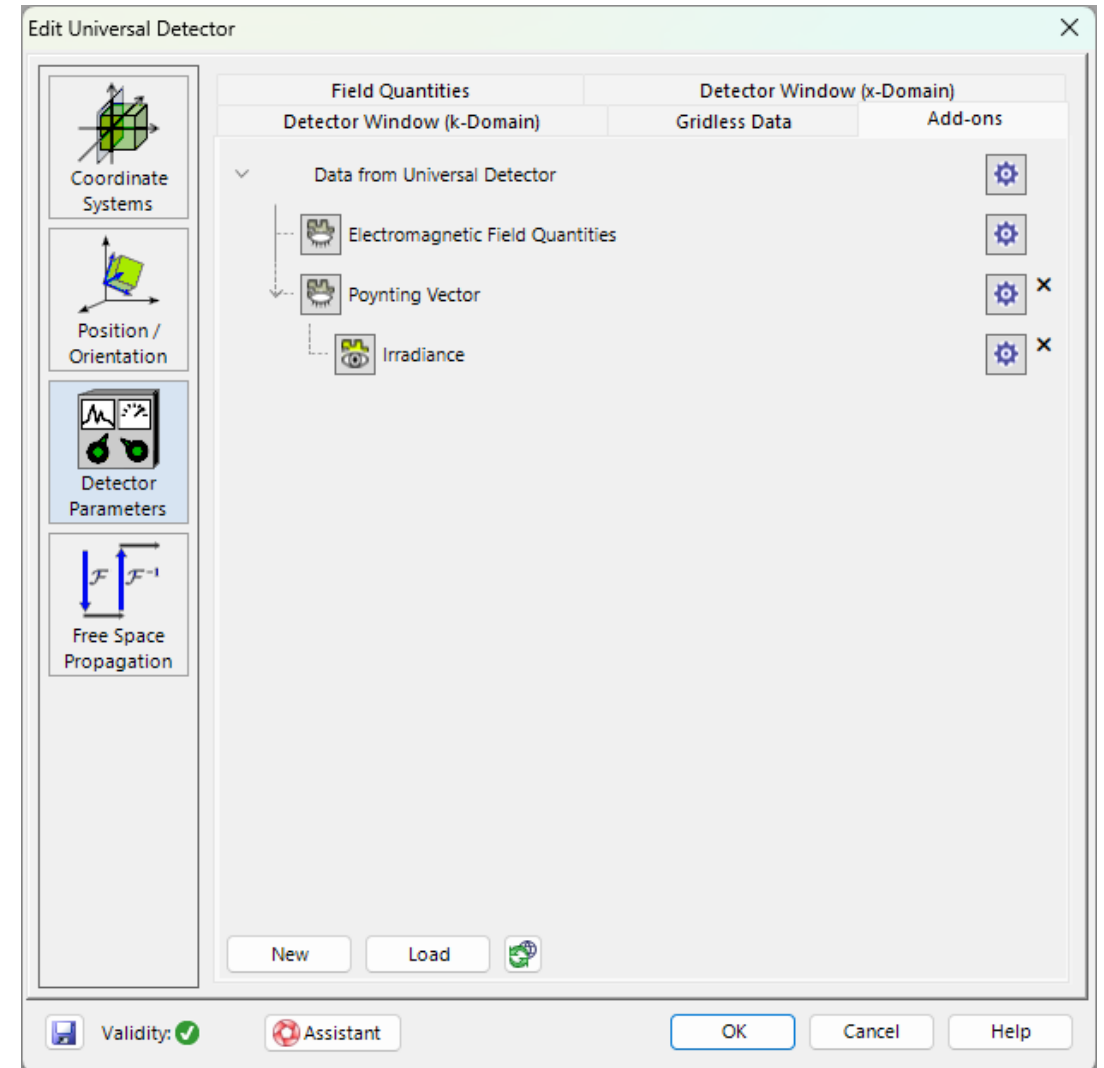
The *Microstructure Component* models diffractive structures using advanced TEA (Thin Element Approximation). In our example the spiral phase plate is given as a custom *Programmable Surface*. This surface can be included in a *Stack* and then loaded into the *Microstructure Component*.

Detector Addons

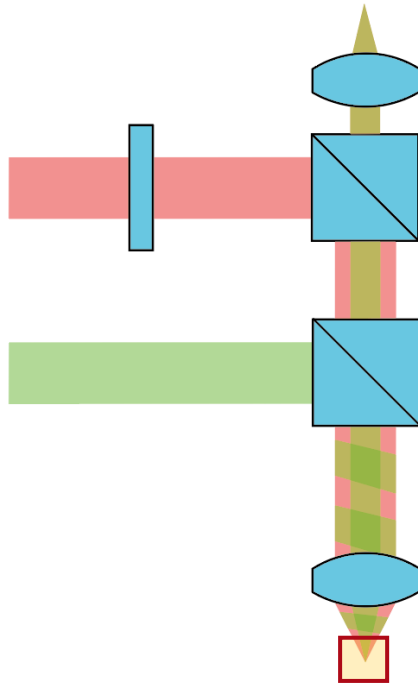


The *Universal Detector* enables the evaluation of the impinging field and the calculation of various physical quantities through so-called *Add-Ons*. In this example, the *Irradiance* is calculated. For more information, see:

[Universal Detector](#)



Parameter Run



The screenshot shows the '21: Parameter Run' dialog box. The 'Parameter Specification' tab is active, showing a table with one parameter to be varied.

1	2	*	Object	Category	Parameter	Vary	From	To	Steps
			"Universal Detect...	Basal Positioning...	Distance...	<input checked="" type="checkbox"/>	995 μ m	1.005 mm	101

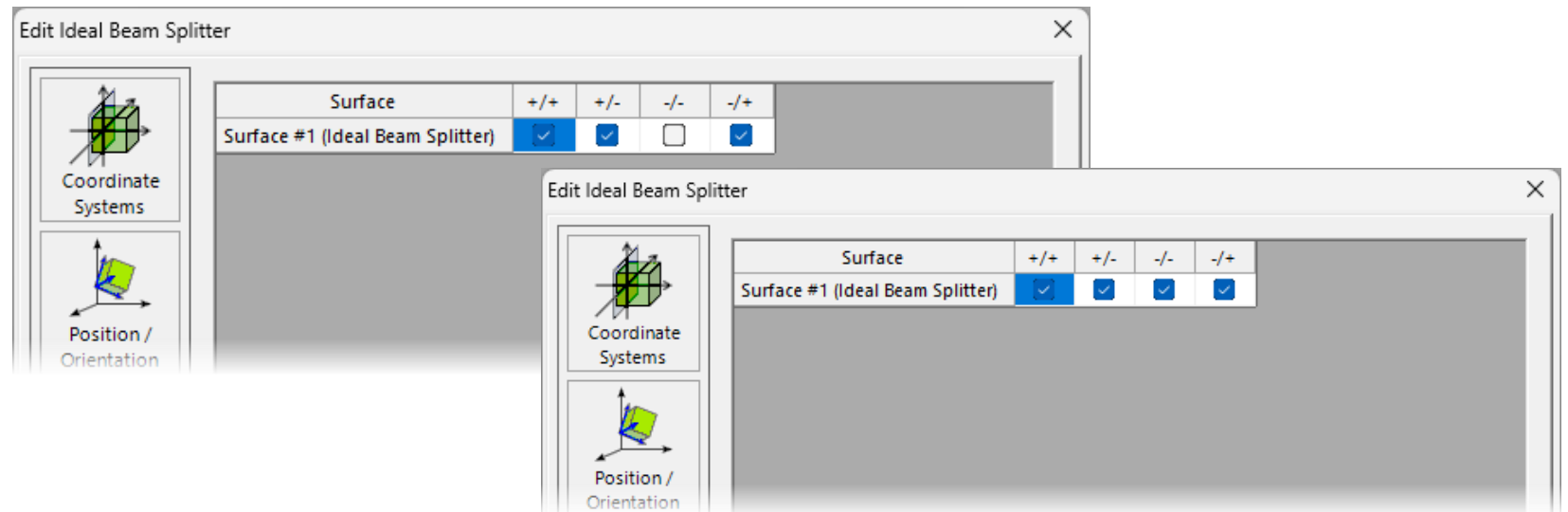
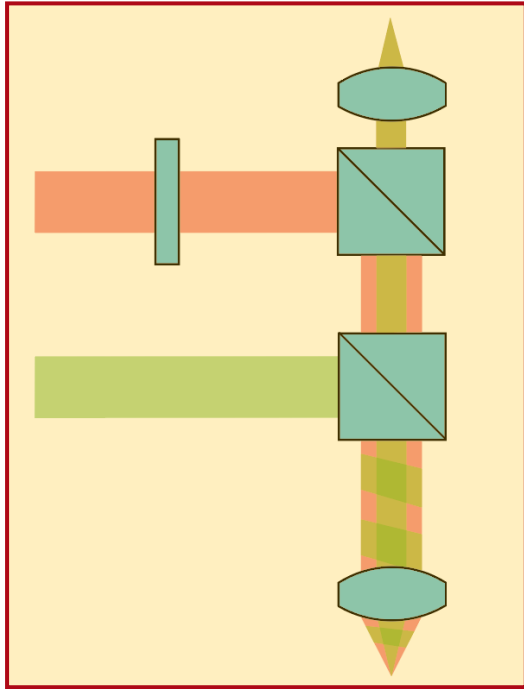
The 'Results' tab is also visible, showing a table with data for iteration steps 77 and 78.

		Iteration Step		
Detector	Subdetector	Combined Output	77	78
Varied Parameters	Distance Before ("Universal...	Data Array	1.0026 mm	1.0027 mm
"Universal Detector" (# 603...	Irradiance	2D Chromatic \downarrow	Chromatic Fields Set 1D	Chromatic Fields Set 1D Chroma

To achieve a z-scan of the focal region a *Parameter Run* can be performed. With this tool the user can easily vary an individual parameter or a set of parameters of the entire optical system. For more information, see:

[Usage of the Parameter Run Document](#)

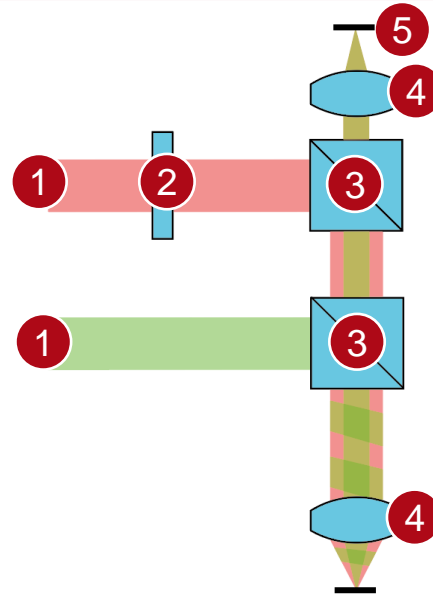
Non-Sequential Modeling



With the channel configuration mode toggle set to *Manual Configuration*, the user can specify, for each surface in the system, which channels to open for the simulation. When the simulation is run, a preliminary analysis of the active light paths will be performed (by the so-called *Light Path Finder*). The field will then be traced along these light paths by the engine to the detectors present in the system.

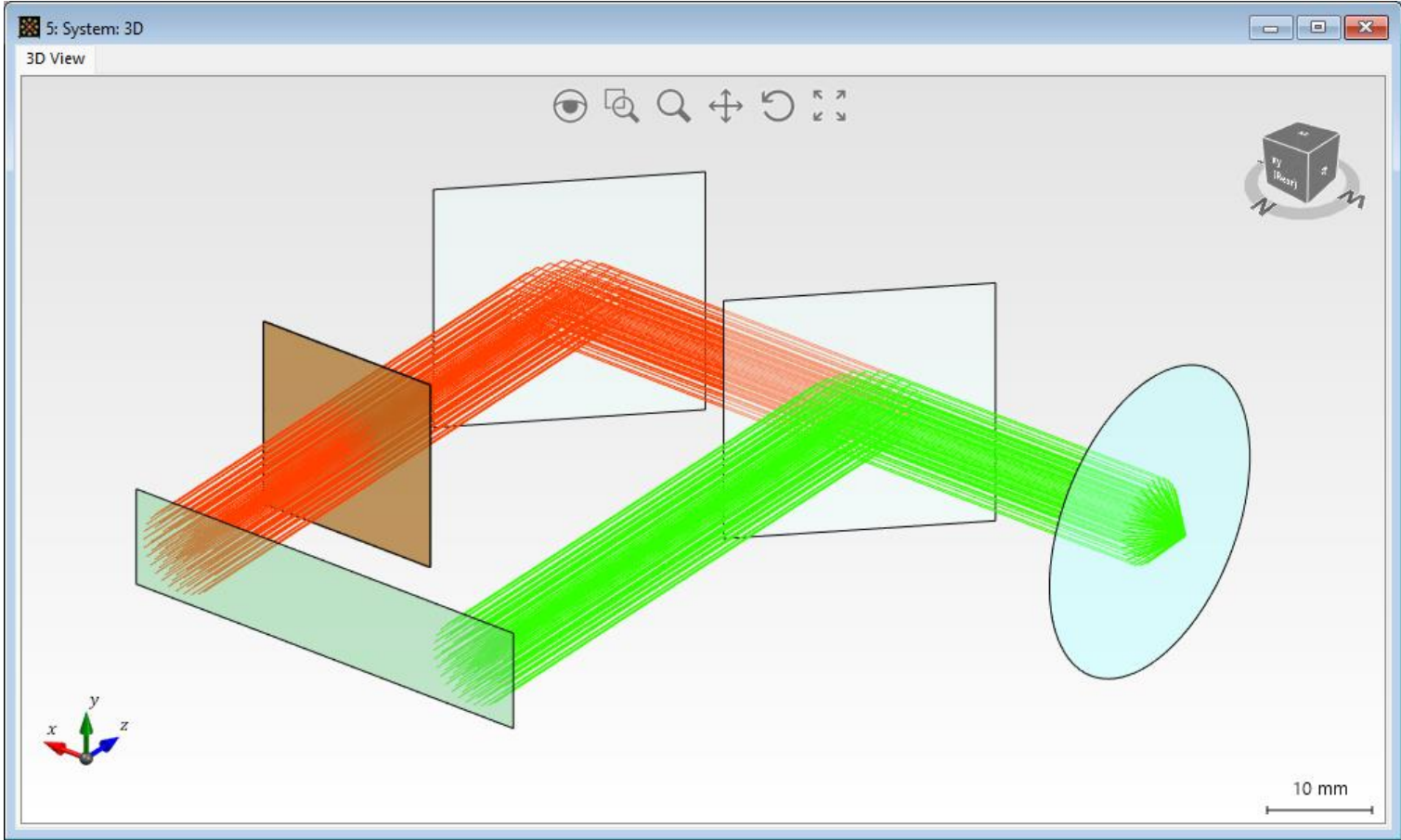
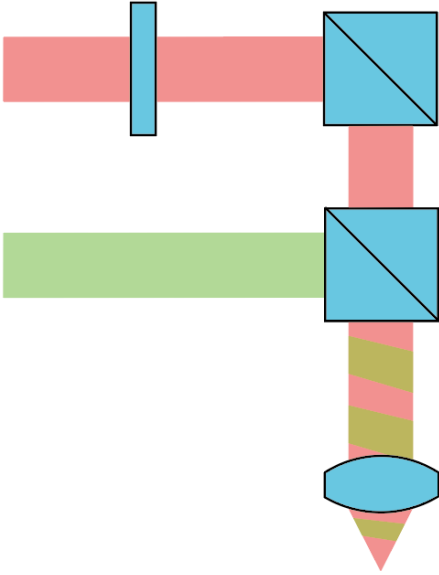
Channel Setting for Non-Sequential Tracing

Summary – Components...

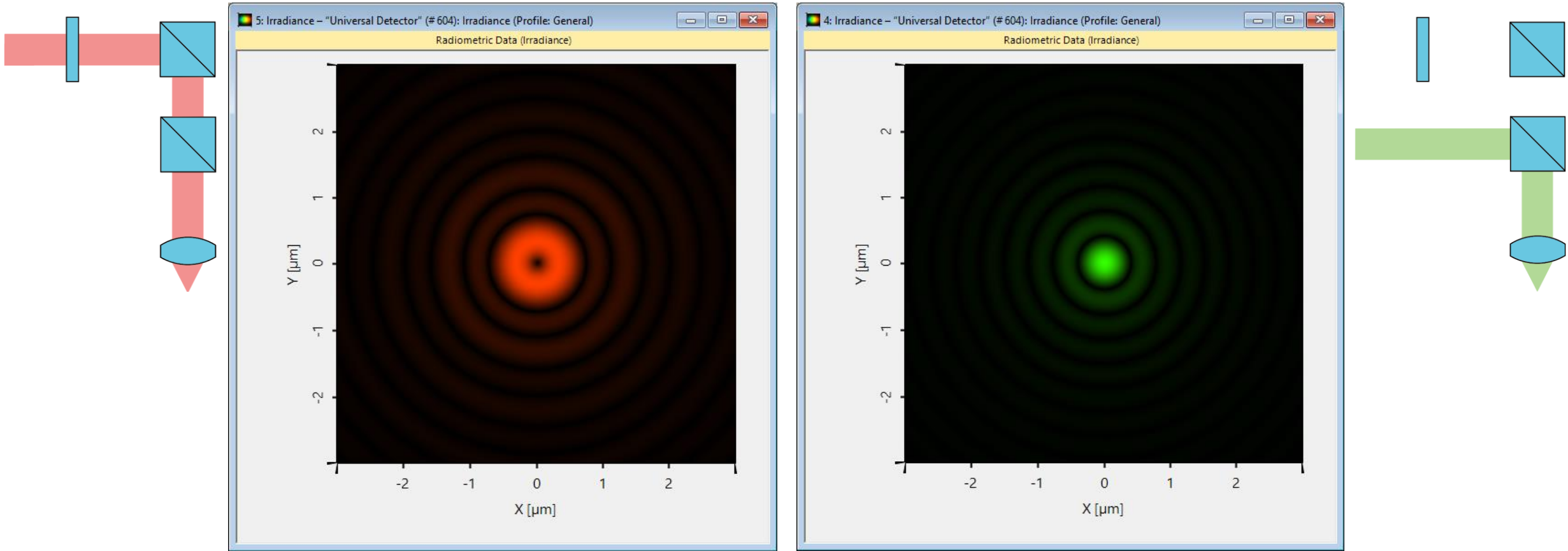


... of Optical System	... in VirtualLab Fusion	Model/Solver/Detected Value
1. source	<i>Multiple Light Source</i>	incoherent spatial source modes
2. phase plate	<i>Microstructure Component</i>	Advanced Thin Element Approximation
3. beam splitter	<i>Ideal Beam Splitter</i>	transmission function
4. lens	<i>Ideal Lens</i>	transmission function
5. detector	<i>Universal Detector</i>	irradiance

System Impressions

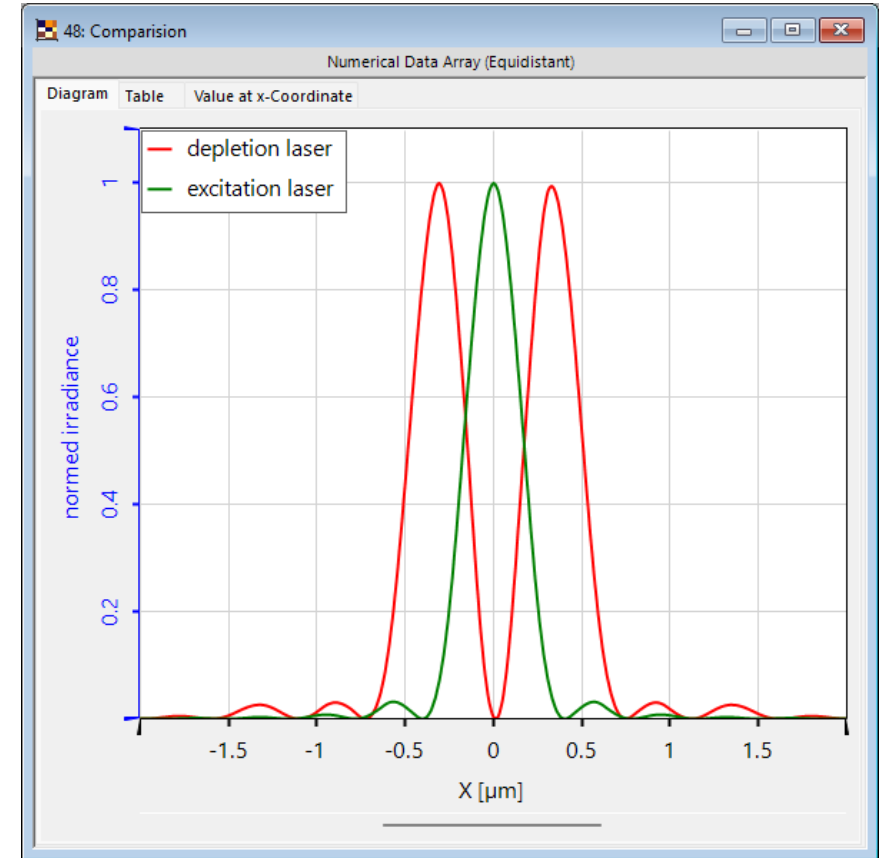
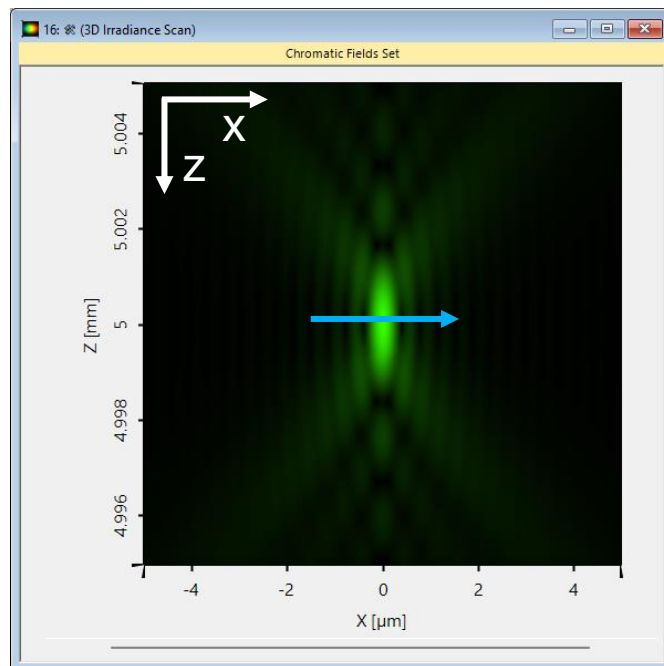
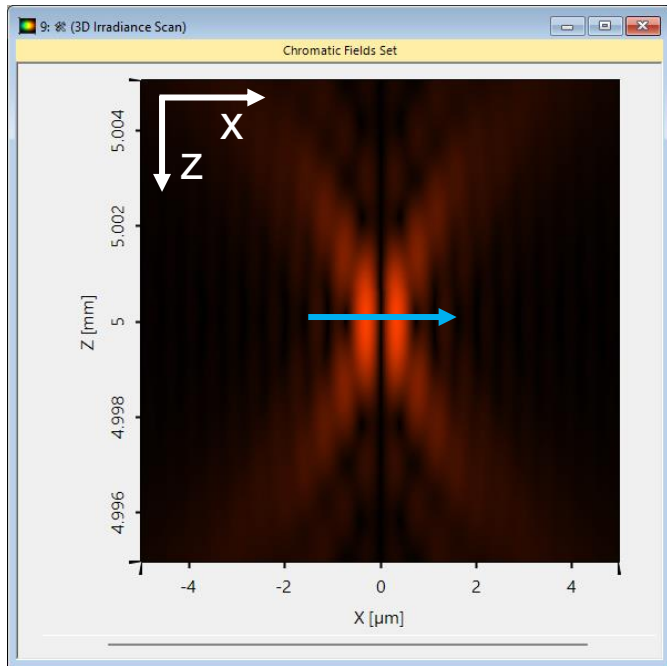
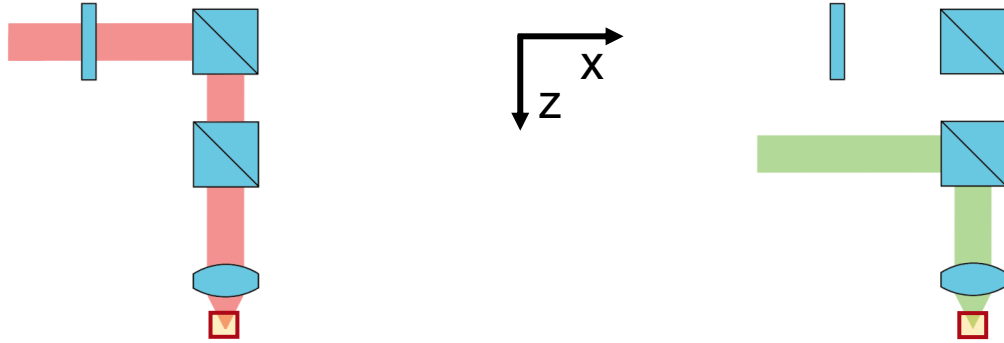


Excitation & Depletion Laser



The propagation of light into the focal region reveals that light from the depletion laser generates a donut-shaped spot, wherein the central hole is smaller than the focal spot of the excitation laser. As the two beams compete in the fluorescence process on the target, this leads to an effective smaller beam size of the signal laser.

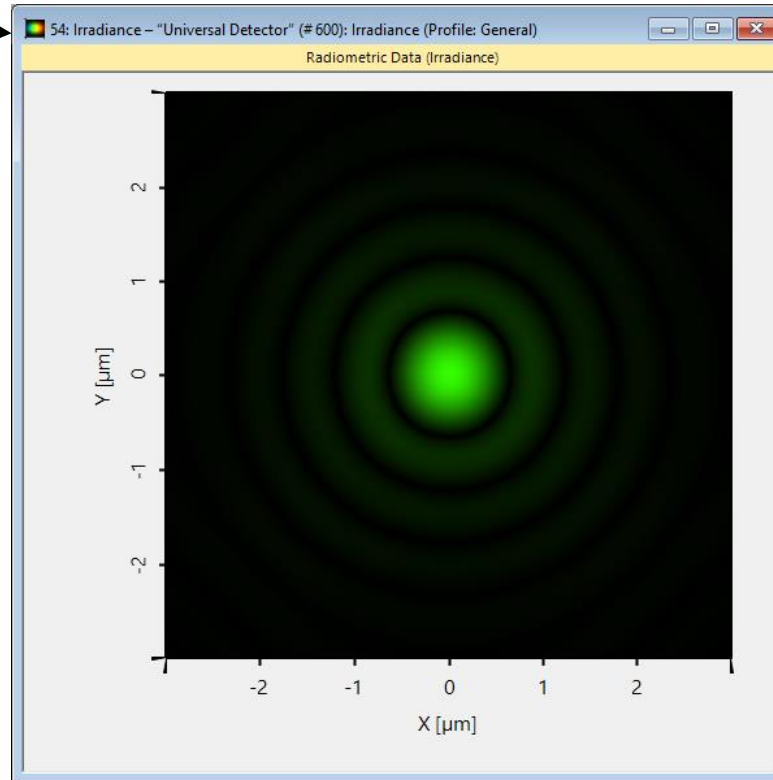
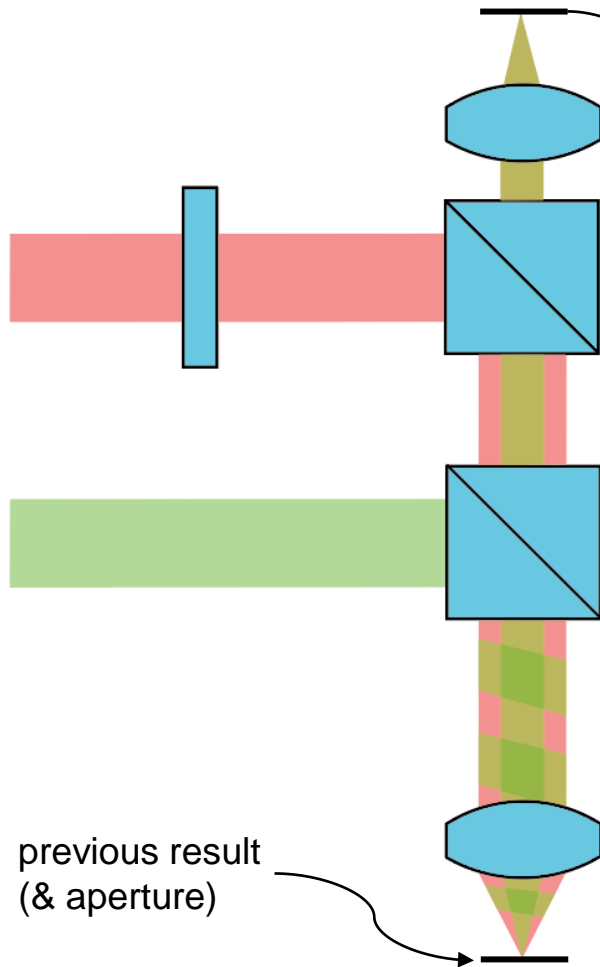
3D STED Profile



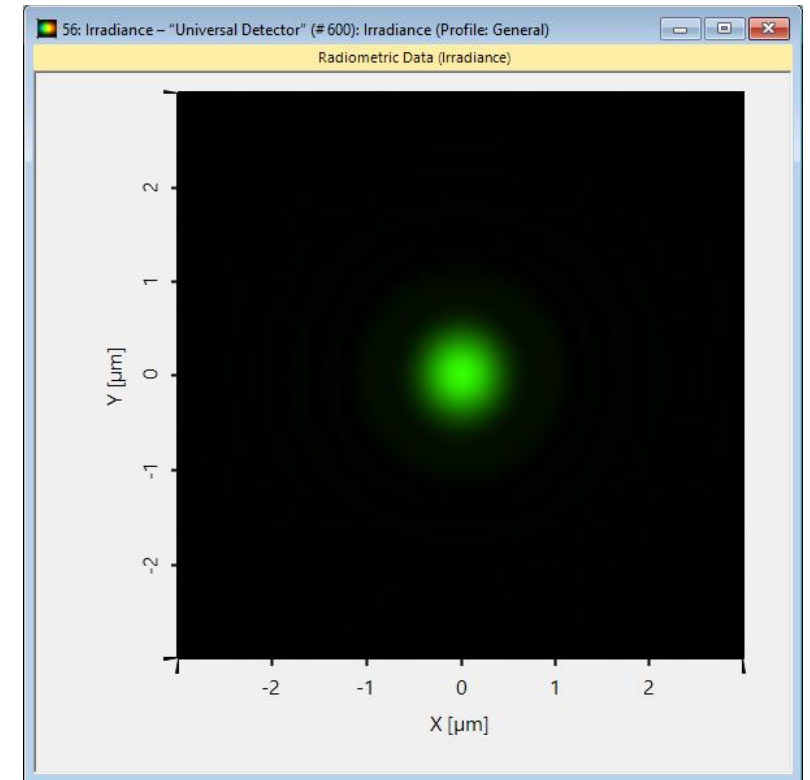
Note: As this simplified example does not include the actual fluorescence effect, we have normalized the two laser beams for visualization purposes.

Stimulated Emission Depletion Effect

To approximate the effect of the saturated depletion, we applied an aperture effect on the result for the excitation laser at the focus position. The parameters of the aperture are roughly based on the focal profile of the depletion laser (600 nm diameter, 25% edge). Propagating back through the system to the detector plane reveals that the spot becomes significantly smaller due to this process.

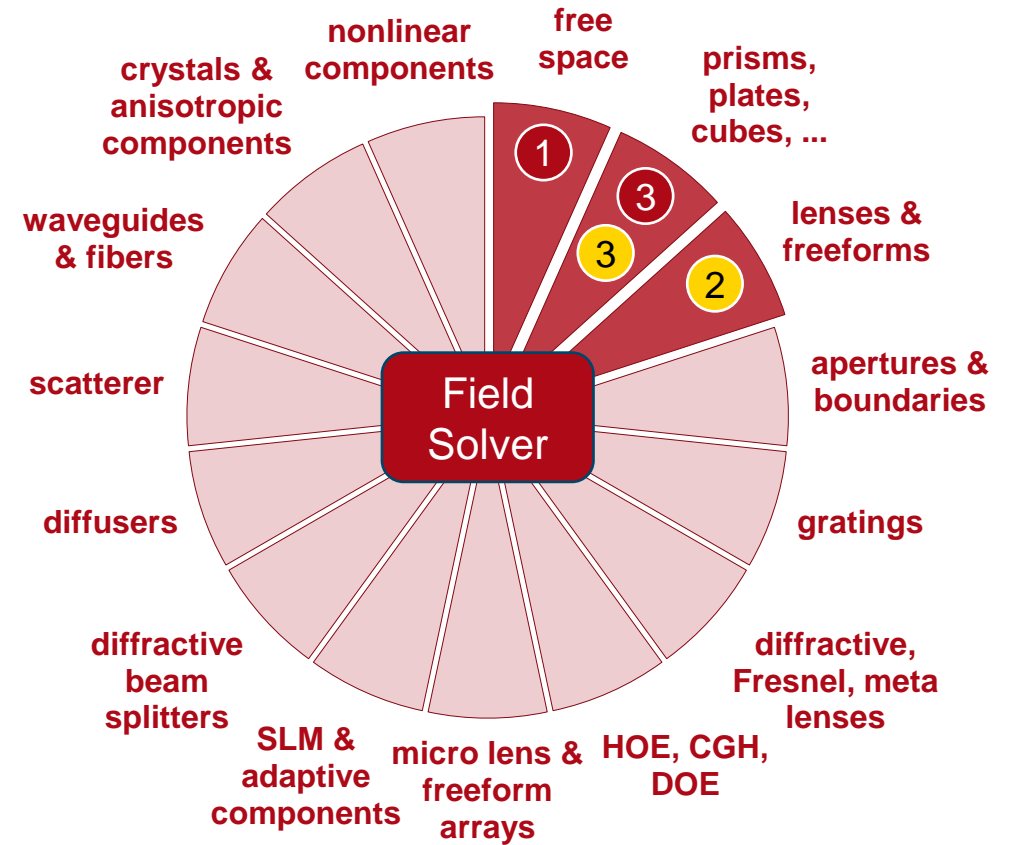
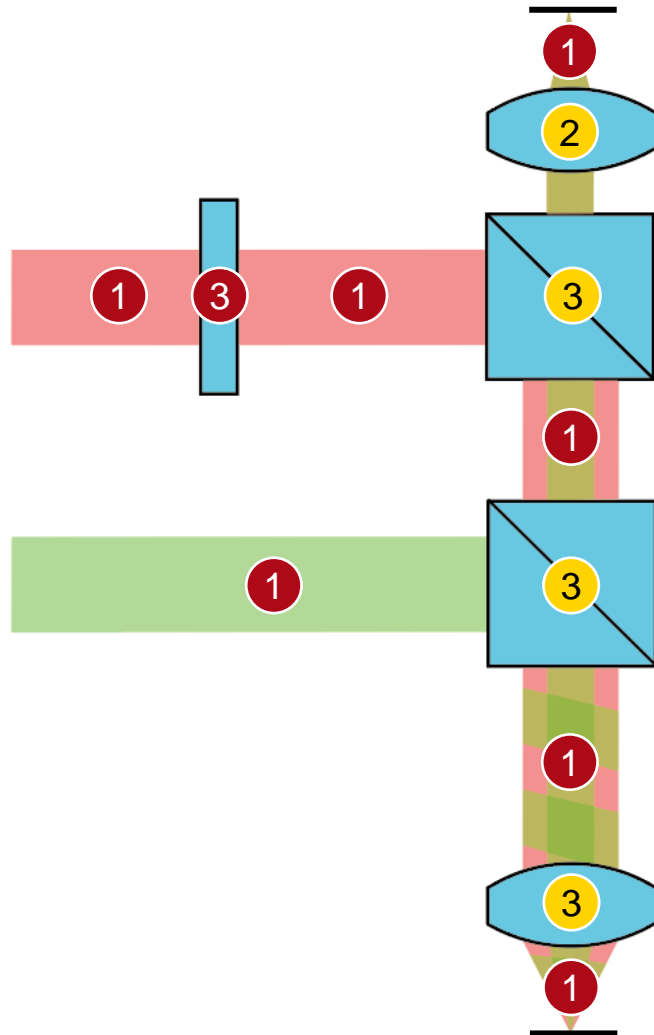


without aperture



with aperture

VirtualLab Fusion Technologies



idealized component

Document Information

title	Principle of Stimulated Emission Depletion (STED) Microscopy
document code	MIC.0024
document version	1.0
software edition	VirtualLab Fusion Basic
software version	2023.1 (Build 1.556)
category	Application Use Case
further reading	<ul style="list-style-type: none">• <u>Simulation of Multiple Light Source in VLF</u>• <u>Focusing of Gaussian-Laguerre Wave for STED Microscopy</u>

Marketing Picture

